however, before the start and after the end of the process by an RAS measurement.

6. (amended) The method of claim 1, wherein the reflectivity at the extreme value of the Fabry-Perot oscillations under consideration is used to determine the process temperature.

7. (amended) The method of claim 1, wherein the process time up to the extreme value of the Fabry-Perot oscillations under consideration is used to determine the growth rate of the layers.

8. (amended) The method of claim 1, wherein, when the process temperature is determined previously, the reflectivity of the extreme value of the Fabry-Perot oscillations of a ternary layer under consideration is used to determine the composition of the layer.

9. (amended) The method of claim 1, wherein the illumination energy is selected in a range, in which the temperature dependence of the real portion of the dielectric function of the participating materials is monotonic.